Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/345,238	CHEN ET AL.
Examiner	Art Unit
Qi Han	2626

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED			
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John Peng: IDS Rich Dorvil	12/13/2007	QH
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